

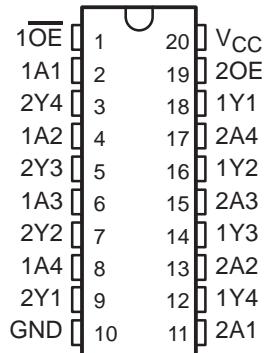
- State-of-the-Art BiCMOS Design Significantly Reduces  $I_{CCZ}$
- ESD Protection Exceeds 2000 V Per MIL-STD-883C, Method 3015
- 3-State Outputs Drive Bus Lines or Buffer Memory Address Registers
- Package Options Include Plastic Small-Outline (DW) and Shrink Small-Outline (DB) Packages, Ceramic Chip Carriers (FK) and Flatpacks (W), and Standard Plastic and Ceramic 300-mil DIPs (J, N)

### description

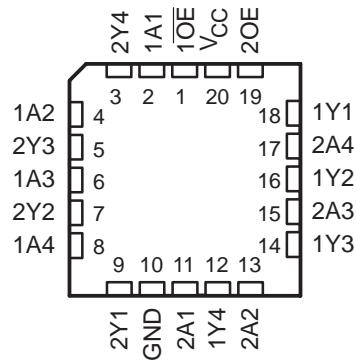
These octal buffers and line drivers are designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. Taken together with the 'BCT240 and 'BCT244, these devices provide the choice of selected combinations of inverting and noninverting outputs, symmetrical  $\overline{OE}$  (active-low output-enable) inputs, and complementary OE and  $\overline{OE}$  inputs.

The SN54BCT241 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ . The SN74BCT241 is characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

SN54BCT241 . . . J OR W PACKAGE  
SN74BCT241 . . . DB, DW OR N PACKAGE  
(TOP VIEW)



SN54BCT241 . . . FK PACKAGE  
(TOP VIEW)



### FUNCTION TABLES

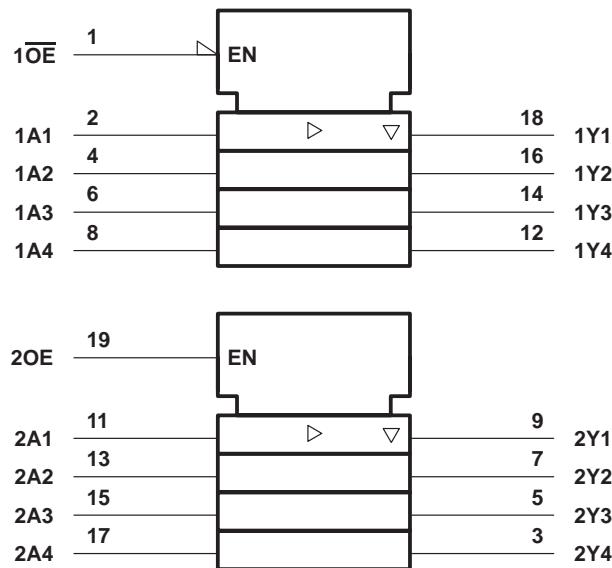
INPUTS		OUTPUT
1OE	1A	1Y
L	H	H
L	L	L
H	X	Z

INPUTS		OUTPUT
2OE	2A	2Y
H	H	H
H	L	L
L	X	Z

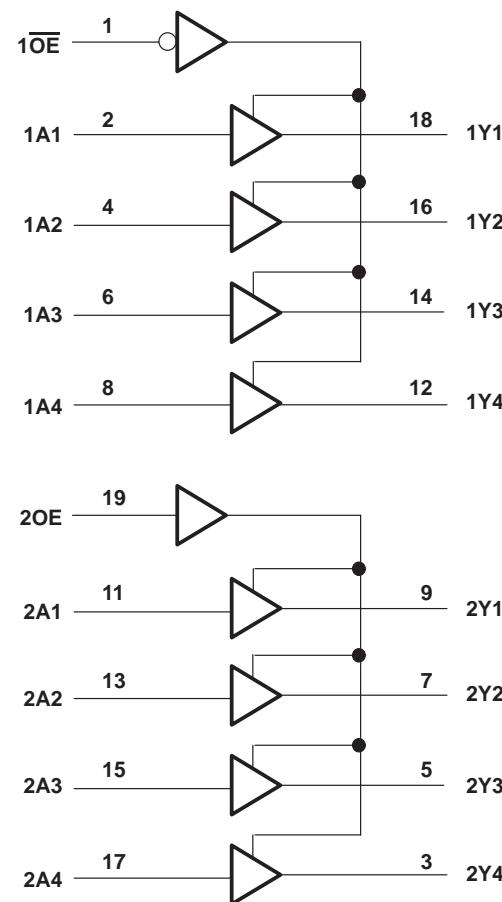
# SN54BCT241, SN74BCT241 OCTAL BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

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## logic symbol†



## logic diagram (positive logic)



**absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡**

‡ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

**recommended operating conditions**

		SN54BCT241			SN74BCT241			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V <sub>CC</sub>	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V <sub>IH</sub>	High-level input voltage	2			2			V
V <sub>IL</sub>	Low-level input voltage			0.8			0.8	V
I <sub>IK</sub>	Input clamp current			-18			-18	mA
I <sub>OH</sub>	High-level output current			-12			-15	mA
I <sub>OL</sub>	Low-level output current			48			64	mA
T <sub>A</sub>	Operating free-air temperature	-55	125	0	0	70		°C

**electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)**

PARAMETER	TEST CONDITIONS	SN54BCT241			SN74BCT241			UNIT
		MIN	TYP†	MAX	MIN	TYP†	MAX	
V <sub>IK</sub>	V <sub>CC</sub> = 4.5 V, I <sub>J</sub> = -18 mA			-1.2			-1.2	V
V <sub>OH</sub>	V <sub>CC</sub> = 4.5 V	I <sub>OH</sub> = -3 mA	2.4	3.3	2.4	3.3		V
		I <sub>OH</sub> = -12 mA	2	3.2				
		I <sub>OH</sub> = -15 mA			2	3.1		
V <sub>OL</sub>	V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 48 mA	0.38	0.55				V
		I <sub>OL</sub> = 64 mA			0.42	0.55		
I <sub>J</sub>	V <sub>CC</sub> = 5.5 V, V <sub>I</sub> = 7 V			0.1			0.1	mA
I <sub>IH</sub>	V <sub>CC</sub> = 5.5 V, V <sub>I</sub> = 2.7 V			20			20	μA
I <sub>IL</sub>	V <sub>CC</sub> = 5.5 V, Any A input	V <sub>I</sub> = 0.5 V	-1		-1			mA
				-1.6			-1.6	
I <sub>OZH</sub>	V <sub>CC</sub> = 5.5 V, V <sub>O</sub> = 2.7 V			50			50	μA
I <sub>OZL</sub>	V <sub>CC</sub> = 5.5 V, V <sub>O</sub> = 0.5 V			-50			-50	μA
I <sub>OS‡</sub>	V <sub>CC</sub> = 5.5 V, V <sub>O</sub> = 0		-100	-225	-100	-225		mA
I <sub>CCH</sub>	V <sub>CC</sub> = 5.5 V, Outputs open		23	43	23	43		mA
I <sub>CCL</sub>	V <sub>CC</sub> = 5.5 V, Outputs open		53	85	53	85		mA
I <sub>CCZ</sub>	V <sub>CC</sub> = 5.5 V, Outputs open		4	10	4	10		mA
C <sub>i</sub>	V <sub>CC</sub> = 5 V, V <sub>I</sub> = 2.5 V or 0.5 V		6		6			pF
C <sub>o</sub>	V <sub>CC</sub> = 5 V, V <sub>O</sub> = 2.5 V or 0.5 V		11		11			pF

† All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C.

‡ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

**SN54BCT241, SN74BCT241  
OCTAL BUFFERS/DRIVERS  
WITH 3-STATE OUTPUTS**

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**switching characteristics (see Note 2)**

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 5\text{ V}$ , $C_L = 50\text{ pF}$ , $R1 = 500\text{ }\Omega$ , $R2 = 500\text{ }\Omega$ , $T_A = 25^\circ\text{C}$			$V_{CC} = 4.5\text{ V to }5.5\text{ V}$ , $C_L = 50\text{ pF}$ , $R1 = 500\text{ }\Omega$ , $R2 = 500\text{ }\Omega$ , $T_A = \text{MIN to MAX}^\dagger$			UNIT	
			'BCT241			SN54BCT241		SN74BCT241		
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
$t_{PLH}$	A	Y	0.5	2.5	4.5	0.5	5.2	0.5	4.9	ns
$t_{PHL}$			1	3	5.4	1	6.3	1	5.9	
$t_{PZH}$	$\overline{OE}$ or OE	Y	1	5.7	7.8	1	9.1	1	8.7	ns
$t_{PZL}$			1	5.2	8.6	1	10	1	9.4	
$t_{PHZ}$	$\overline{OE}$ or OE	Y	1	5.8	6.8	1	8.4	1	8.1	ns
$t_{PLZ}$			1	7	8.1	1	11	1	9.9	

<sup>†</sup>For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



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